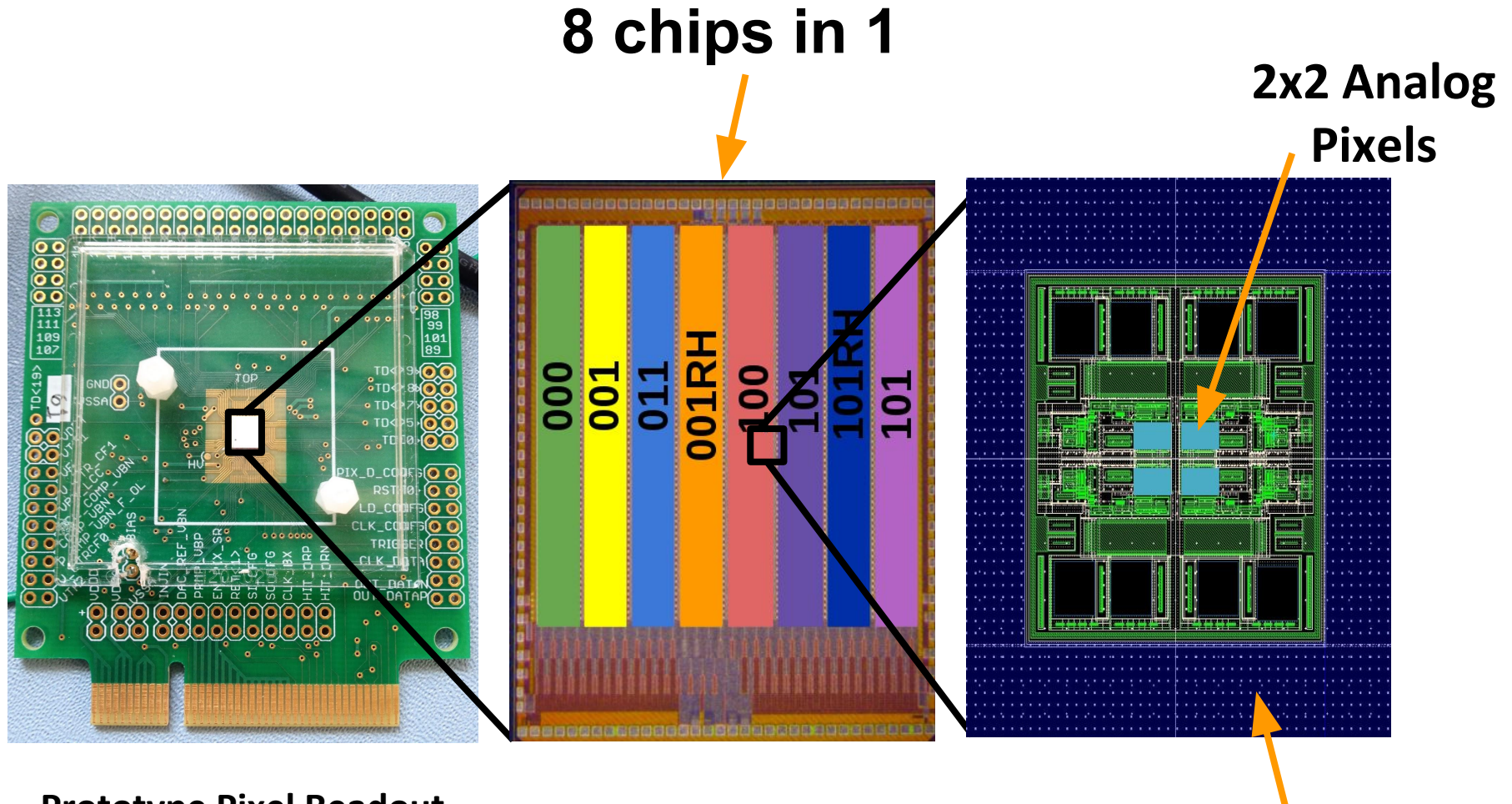


FE65-P2 Timing Dispersion

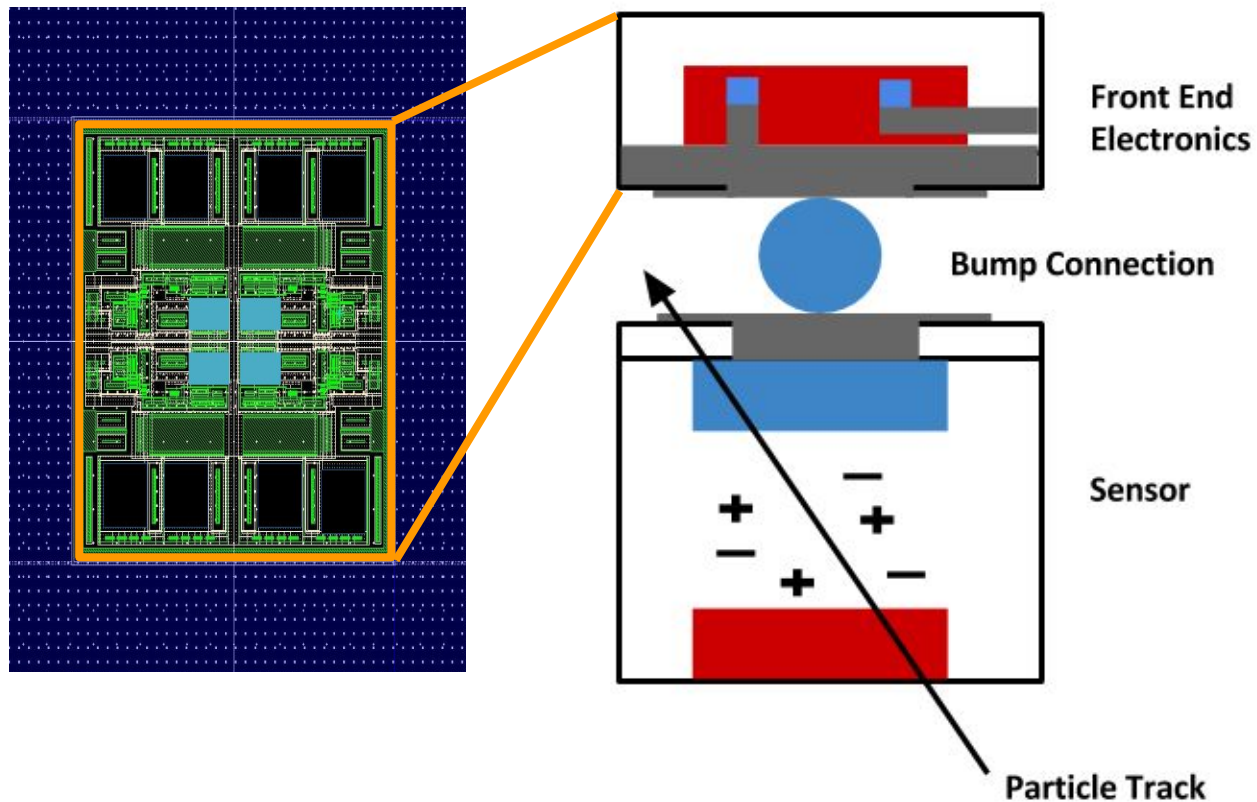
FE65-P2: Overview



Prototype Pixel Readout Chip:

Successor to FE-I4
Predecessor to RD53A

Hybrid Pixel Detectors

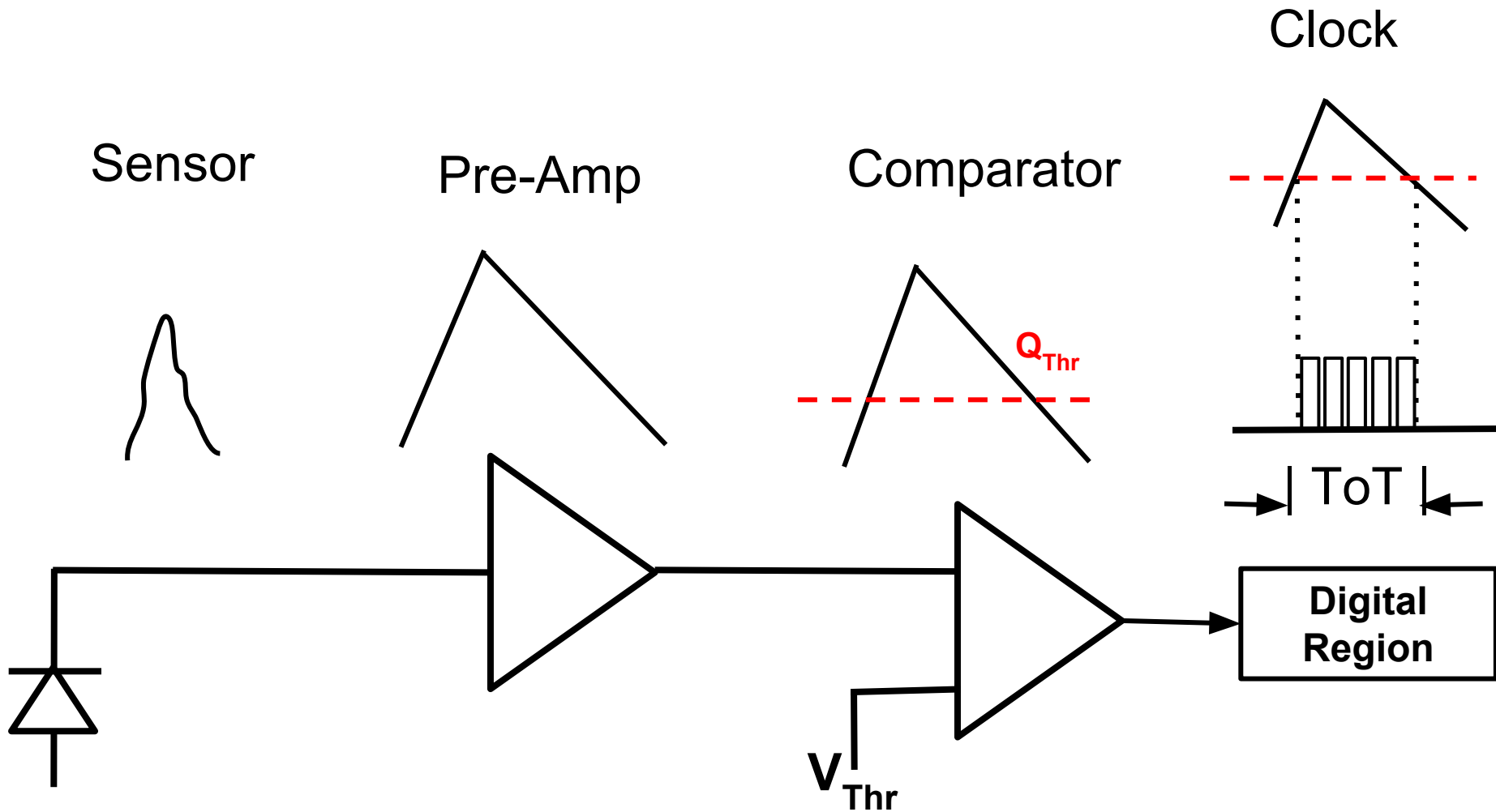


Sensor bump bonded to pads surrounding analog front ends

Charge is collected

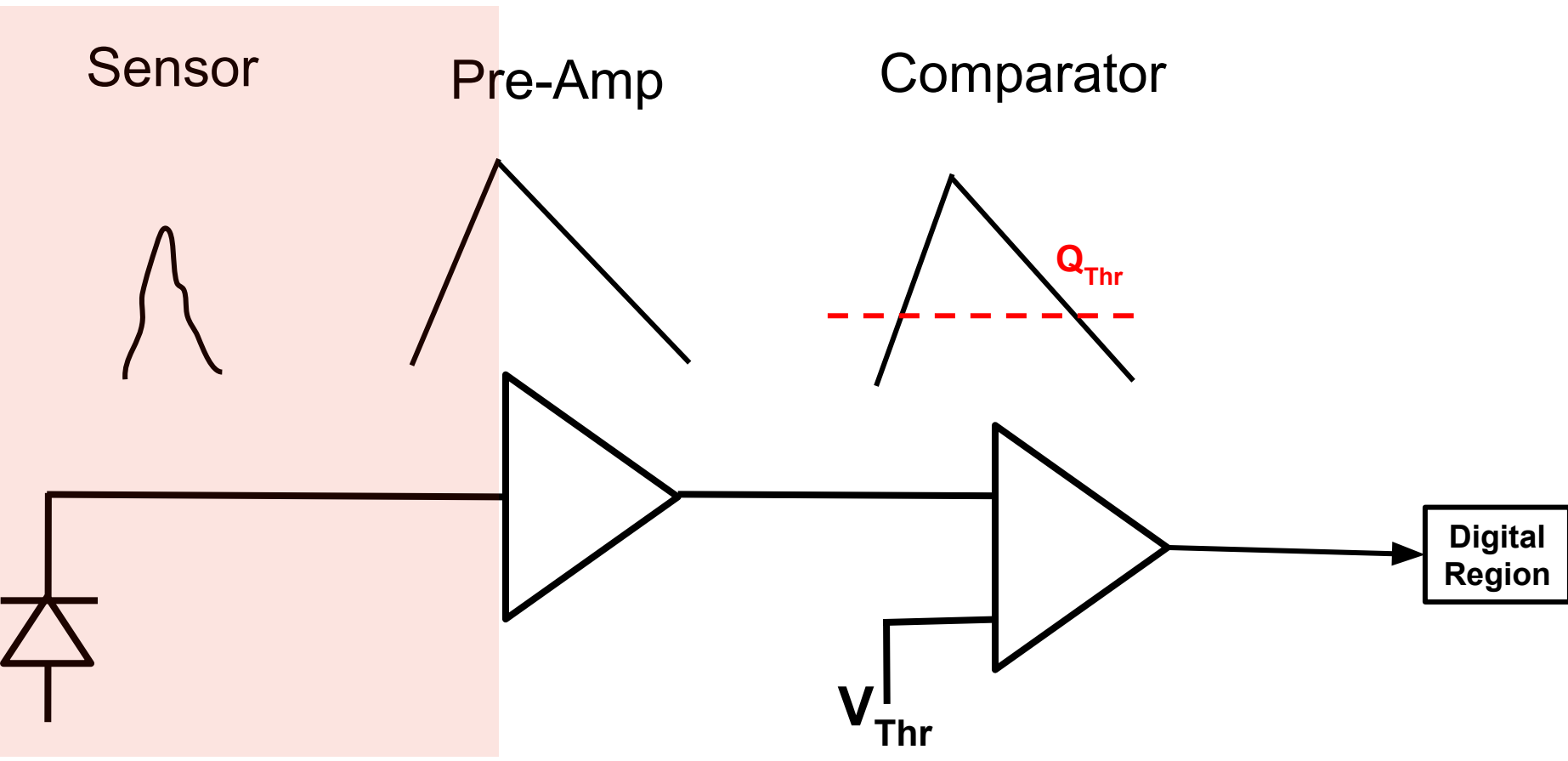
FE65-P2: Overview

Tests done on chip without sensor: hit is simulated with injected charge



Propagation of Delay

Injection ->
Amplifier
Constant



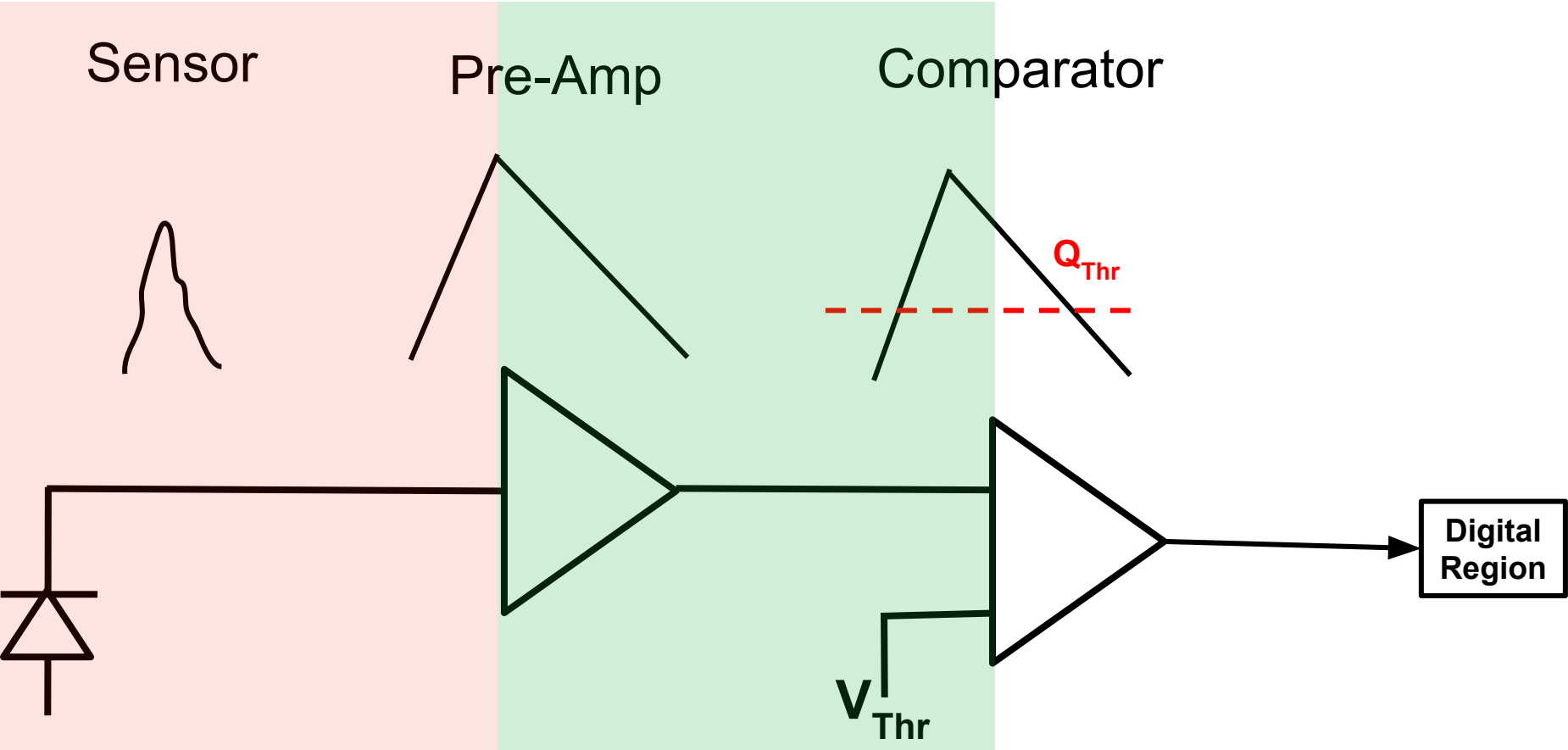
Delay

Injection ->
Amplifier

Constant

Amp -> Crossing
Threshold

Varies with
size of hit



Delay

Injection ->
Amplifier

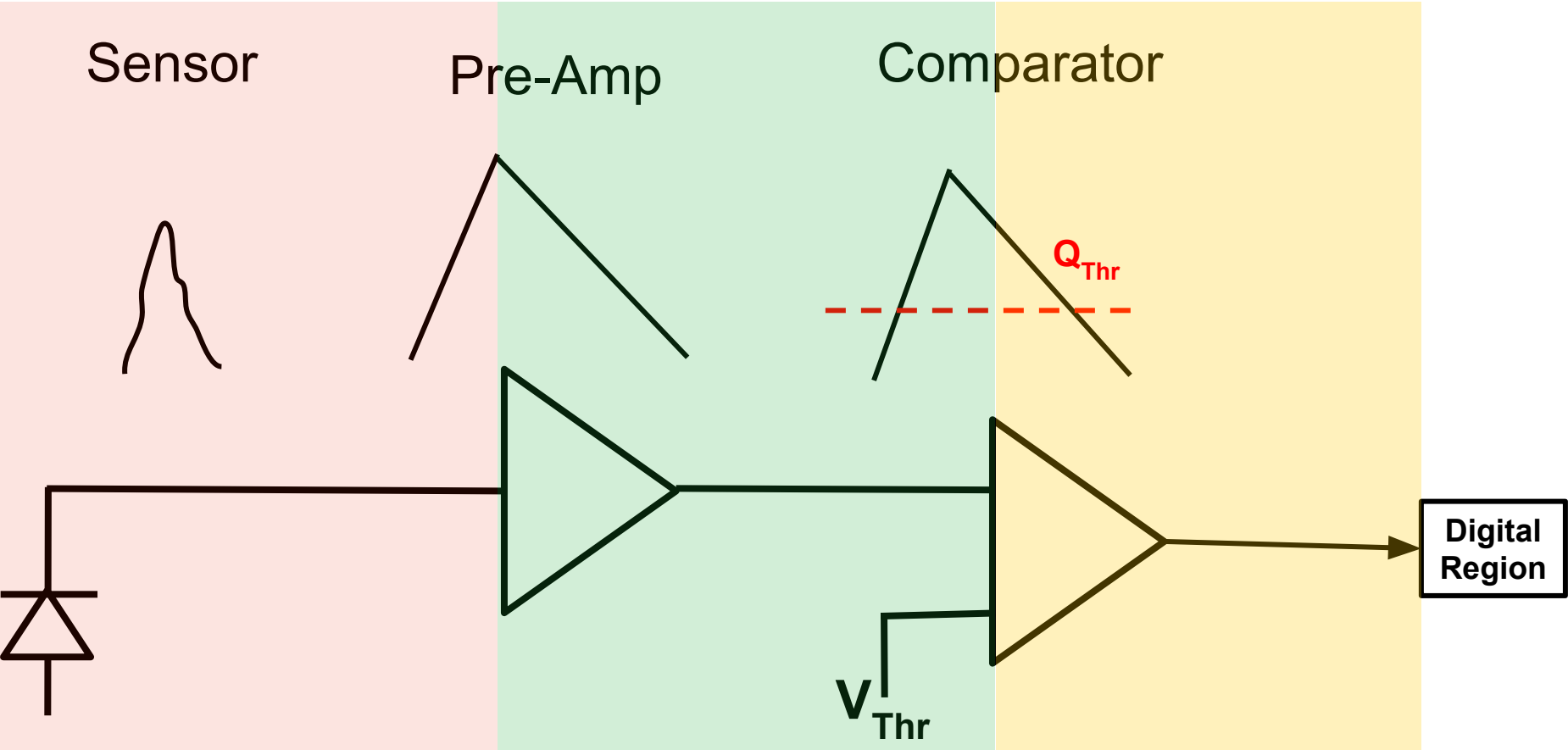
Constant

Amp -> Crossing
Threshold

Varies with
size of hit

Crossing Threshold
-> Comp output

Varies with
Comparator Current



PlsrDelay Measurements

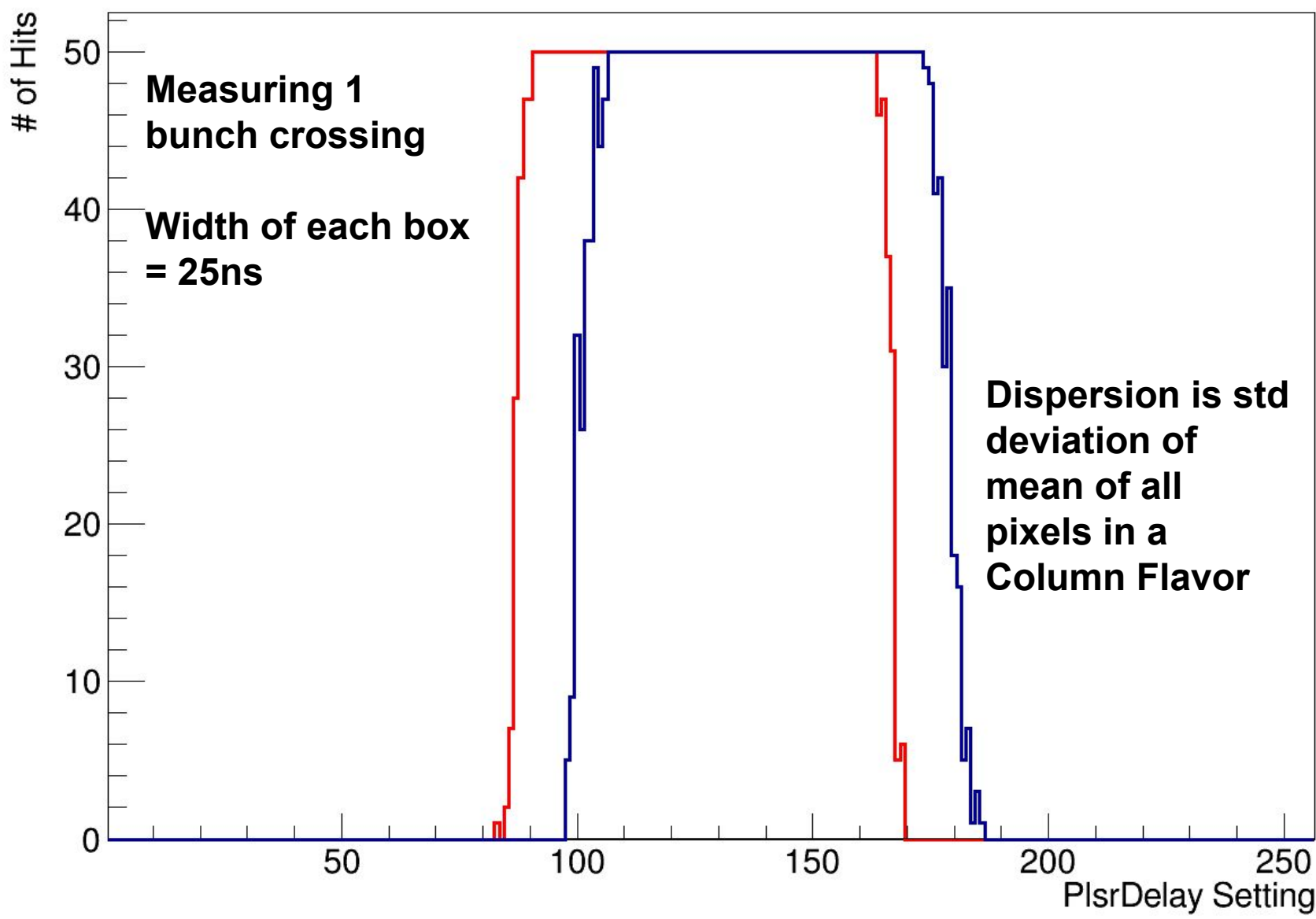
PlsrDelay is a 256 bit register with each bit corresponding to a specific delay in nanoseconds

Global Latency chosen so that sweeping through PlsrDelay settings 0->255 gives rising and falling edge in hit occupancy for each pixel

PlsrDelay scan is run at different Comparator currents
-> controlled by voltage bias: CompVbn

Mean delay in ns of each pixel is recorded

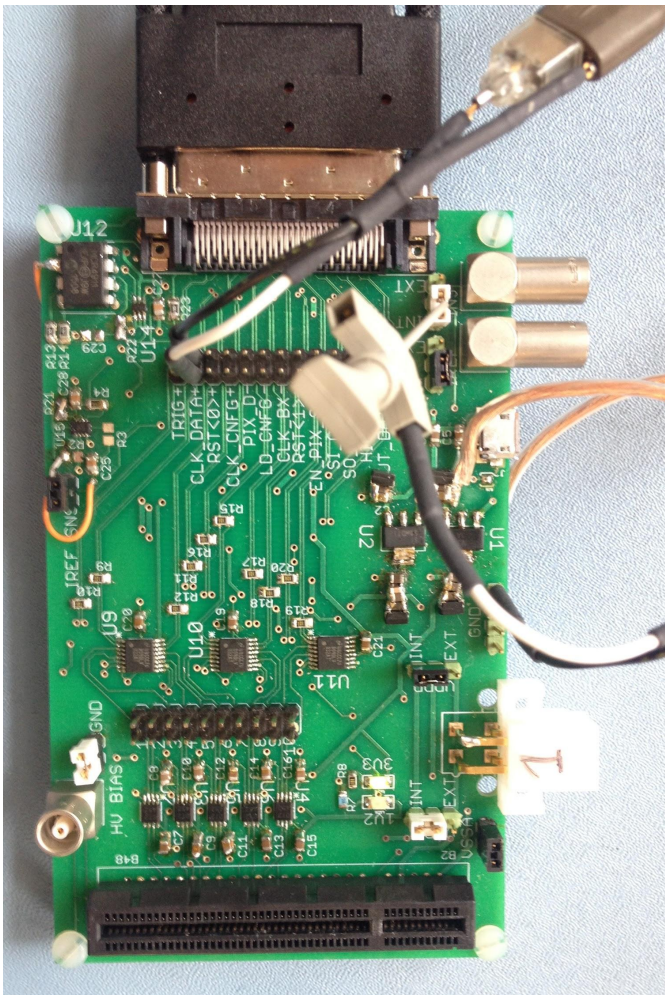
PlsDelay Measurements



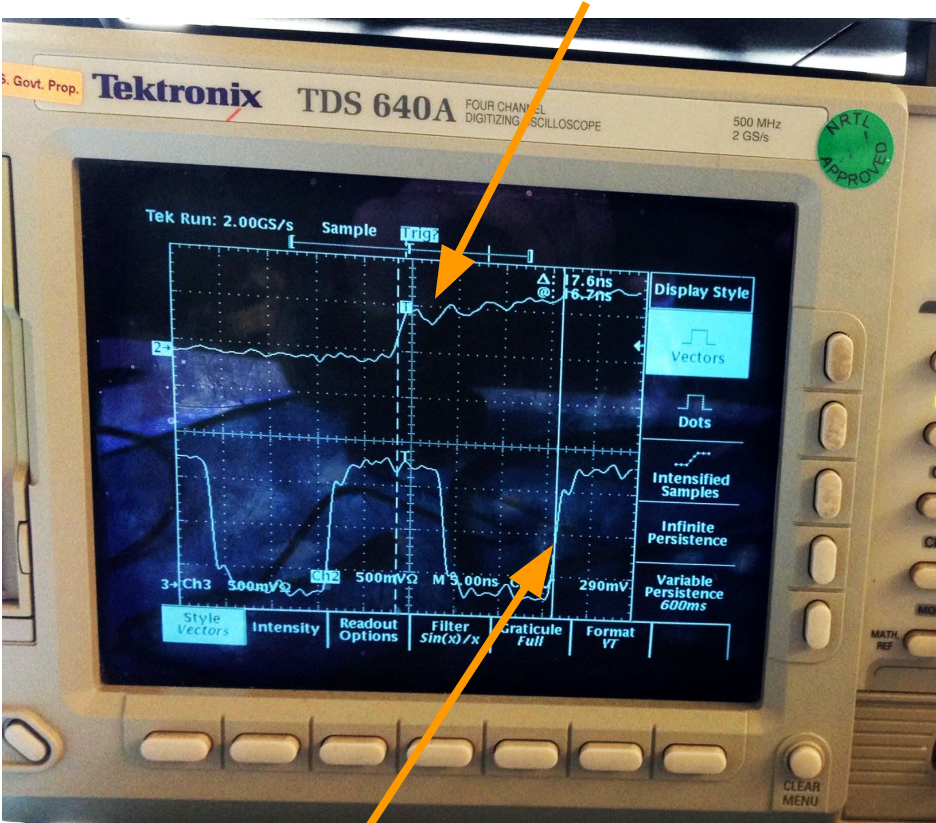
Setting -> Delay Conversion

Delay settings 0->255 must be converted to ns

Injection



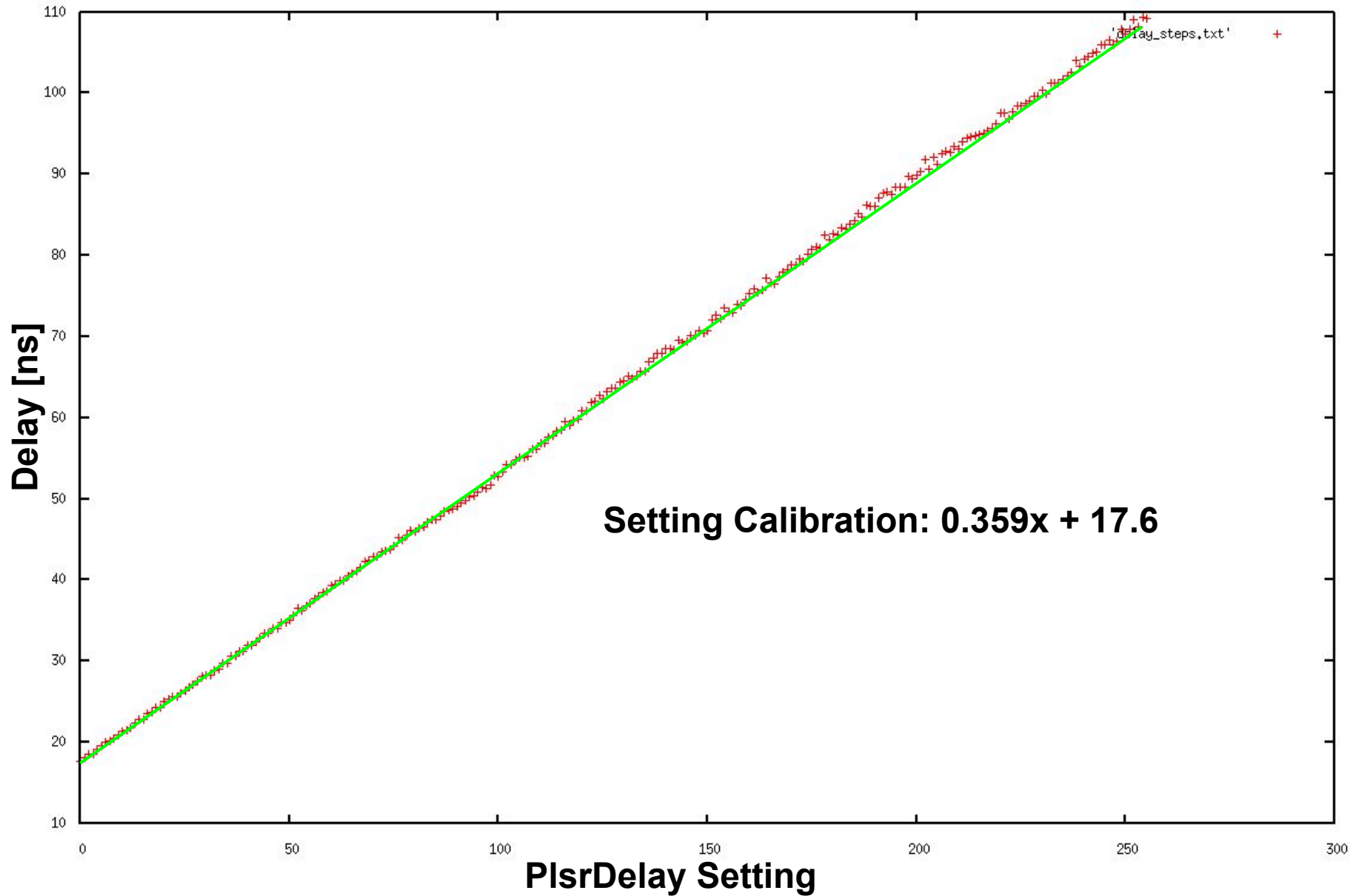
PlsrDelay step size in nanoseconds is a property of test board

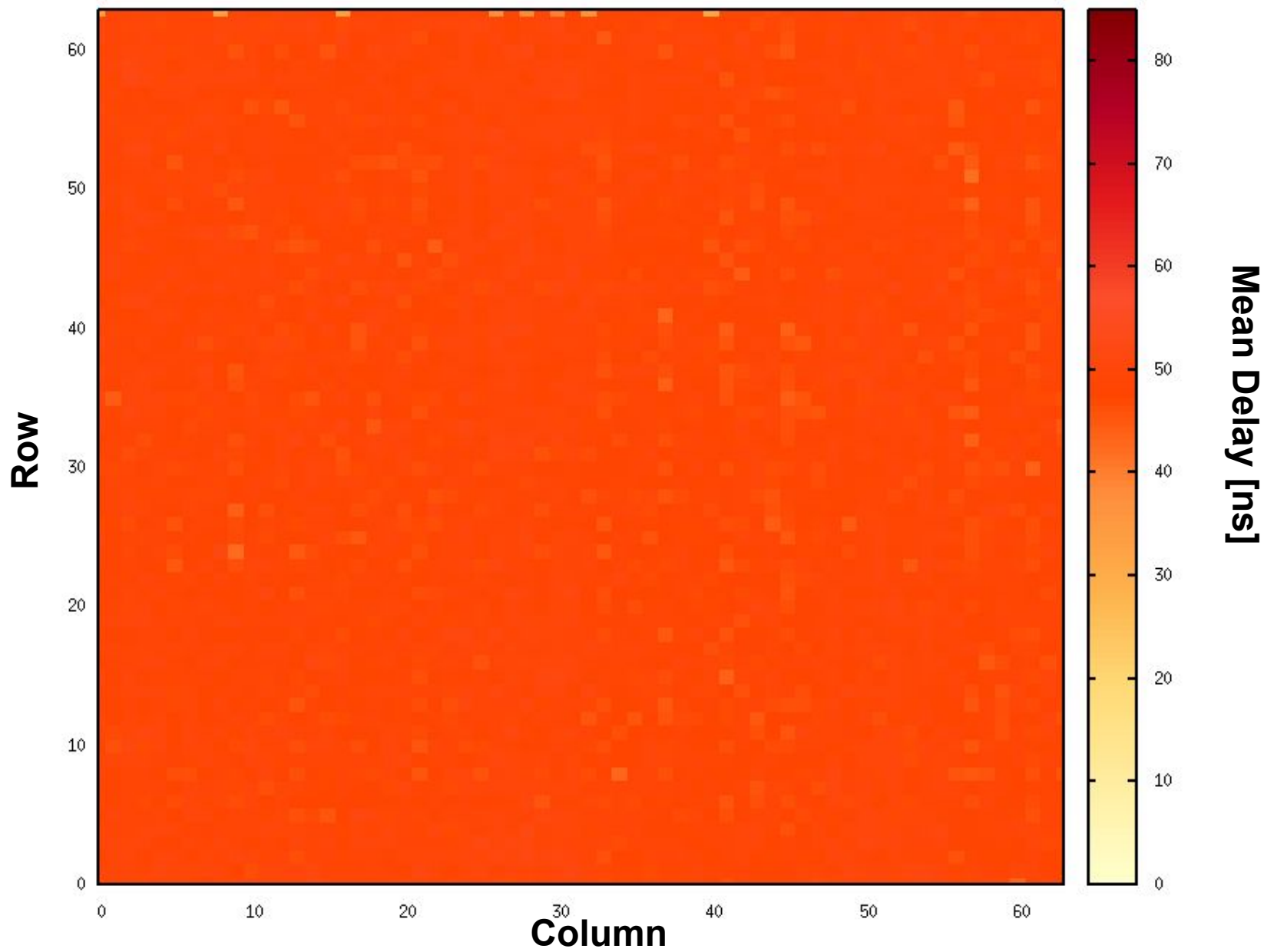


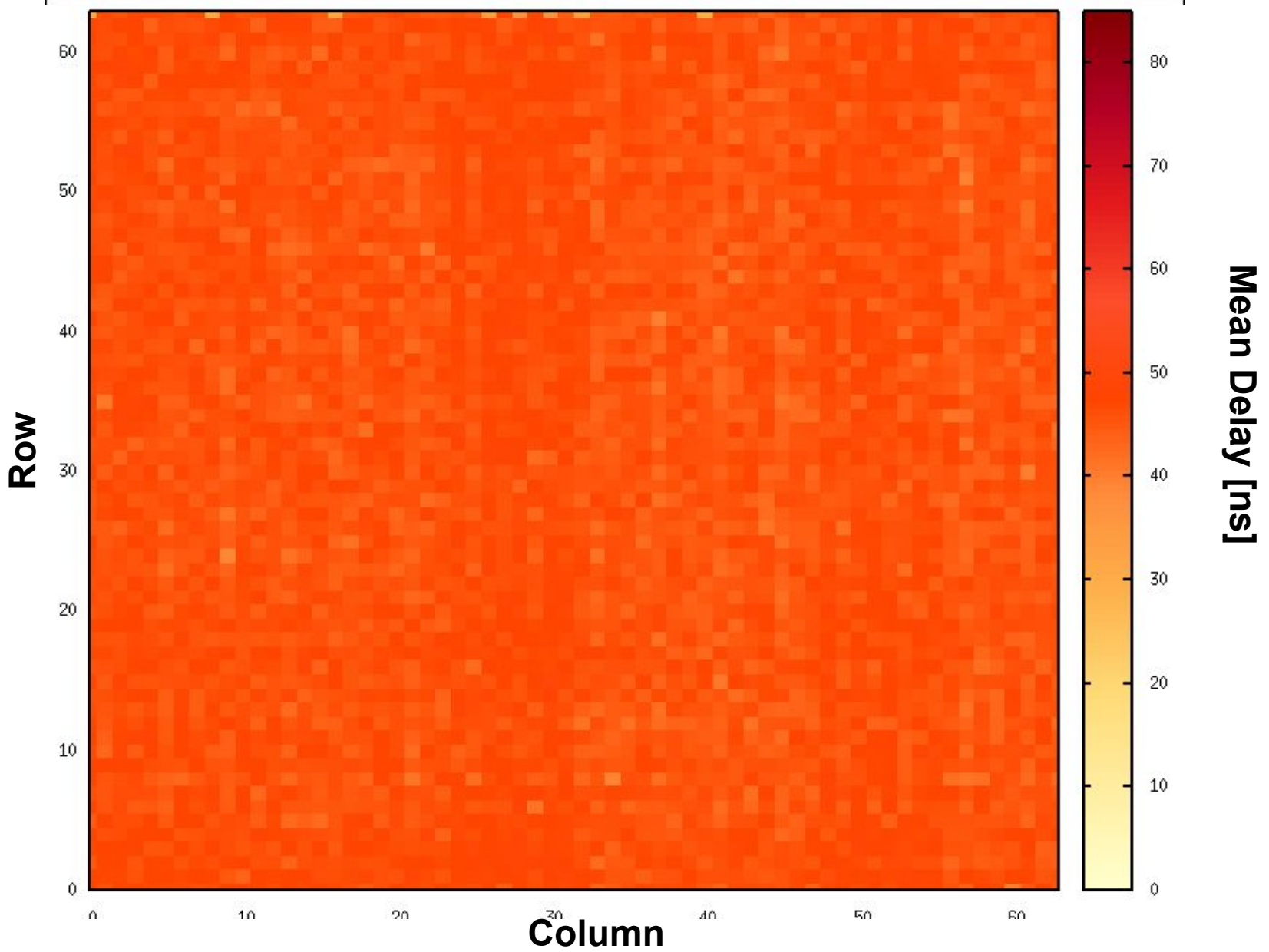
Clock

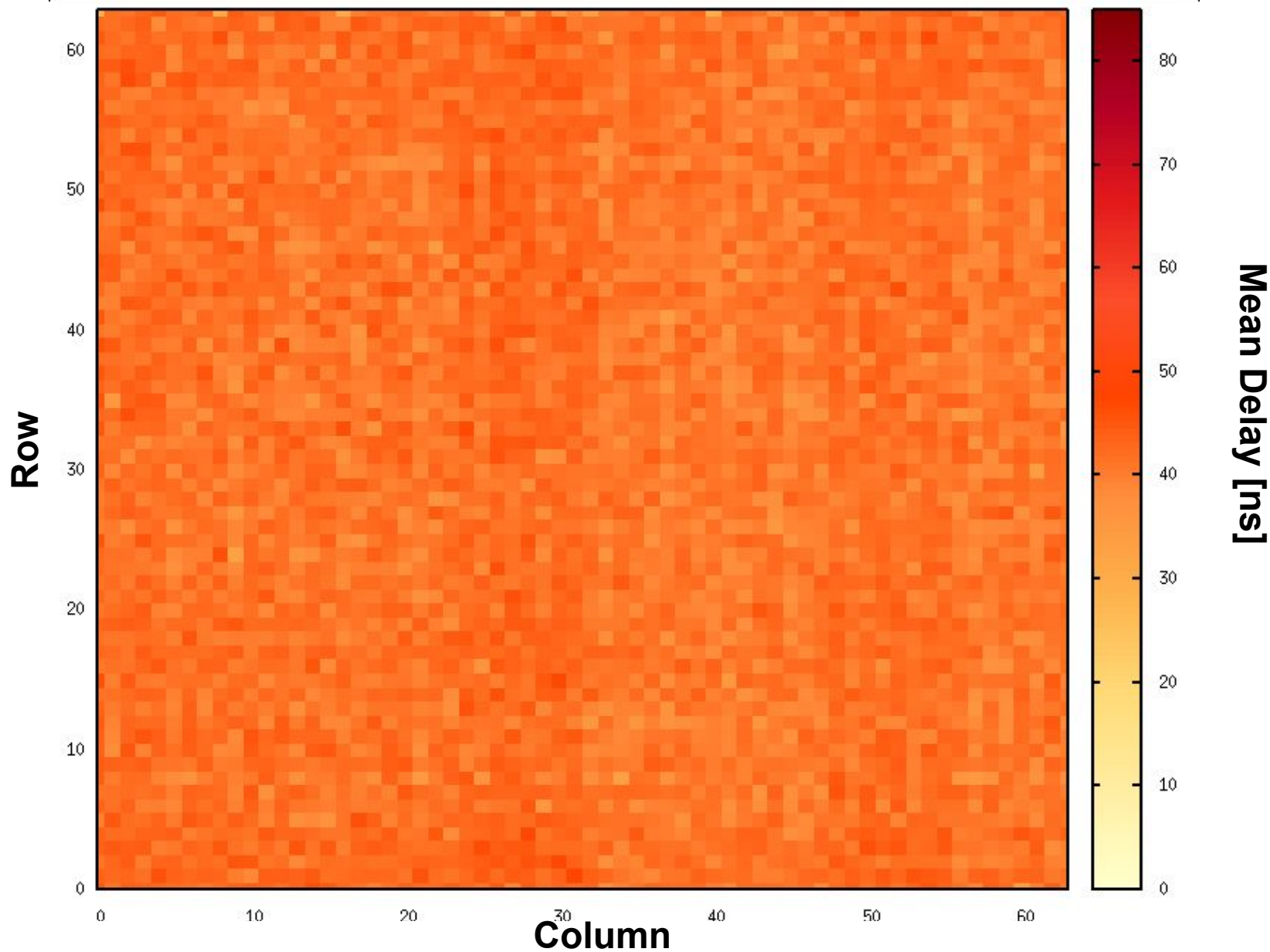
Measure Δt between clock & injection at each PlsrDelay setting

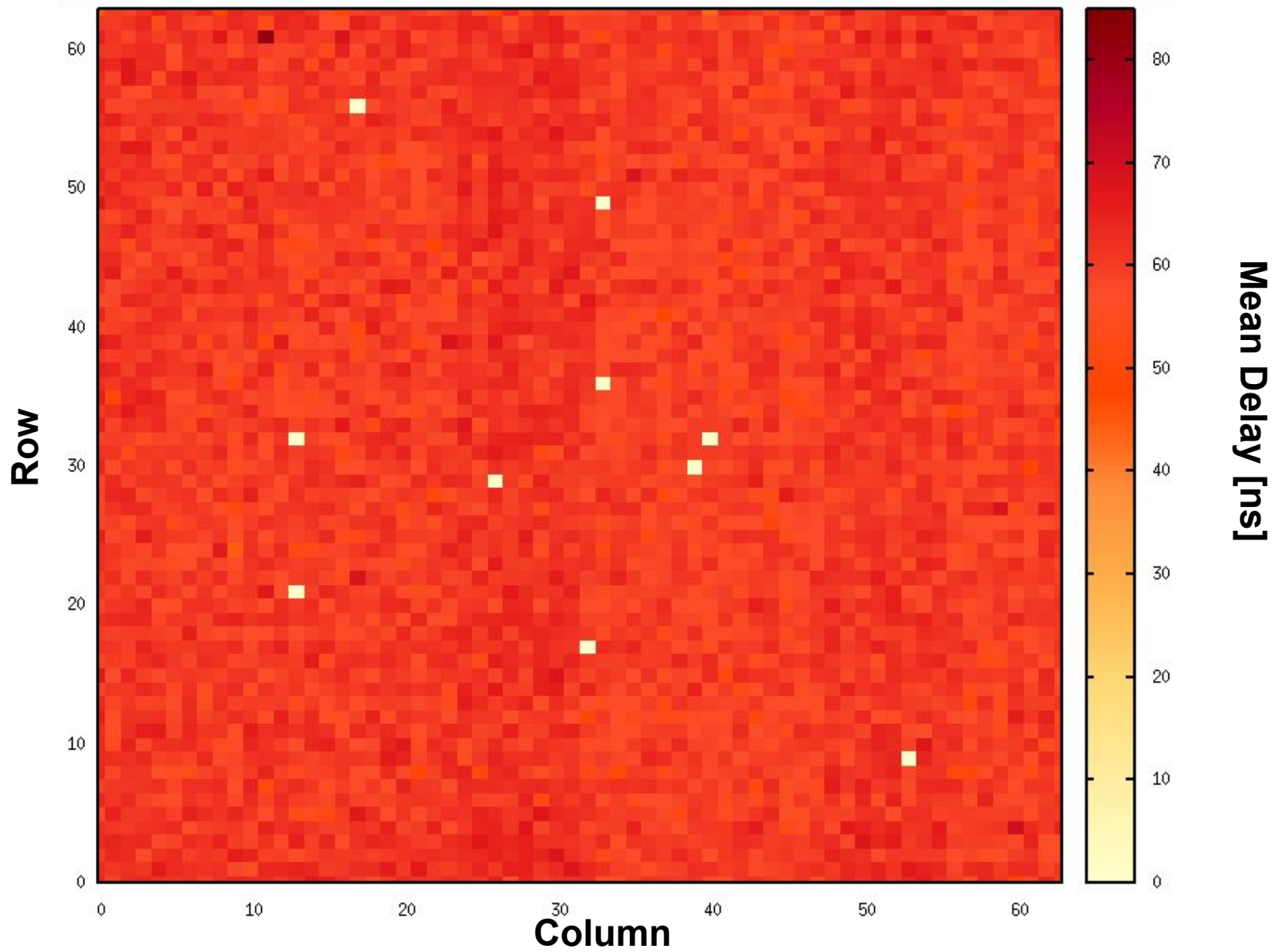
Setting -> Delay Conversion

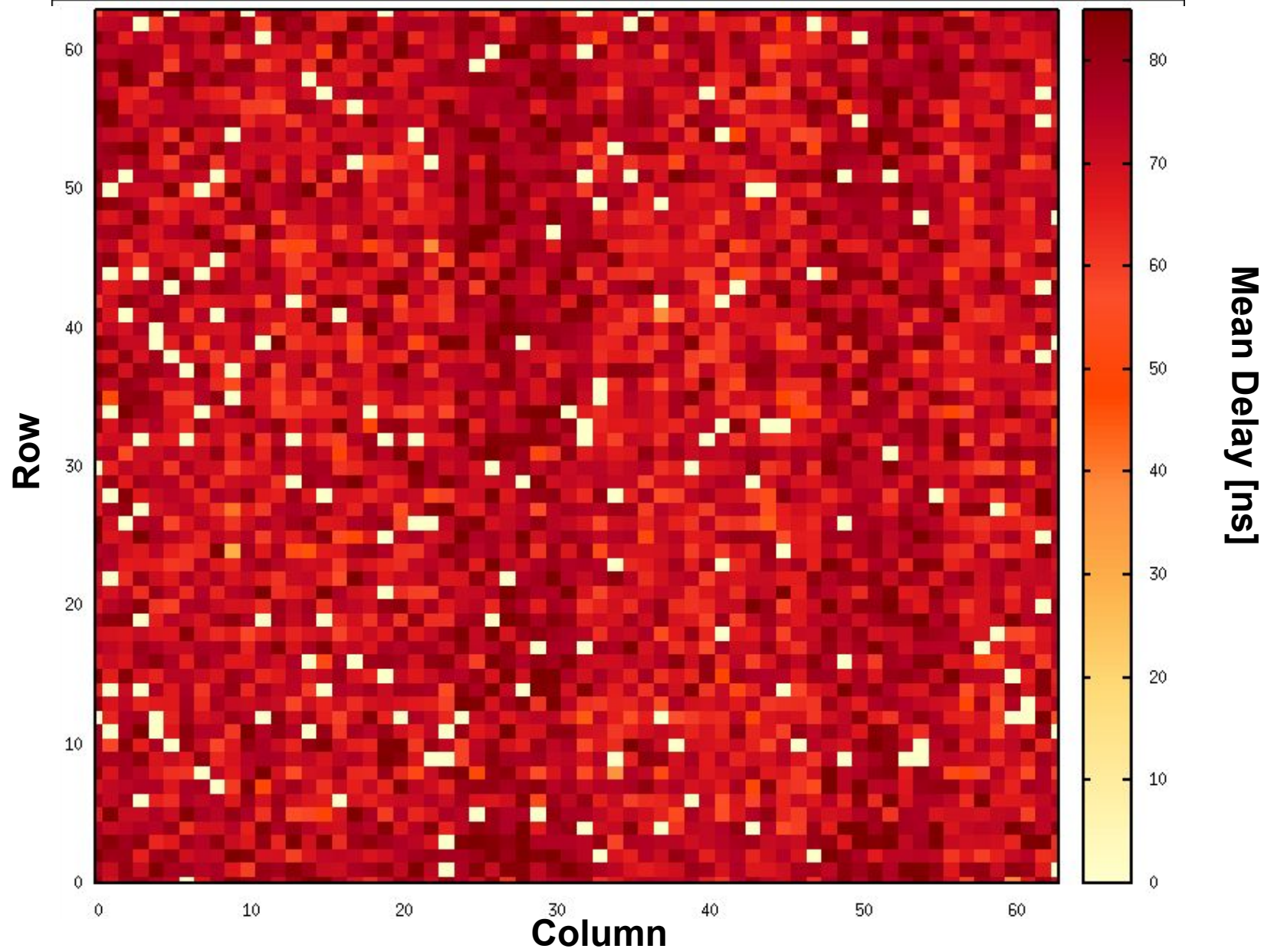




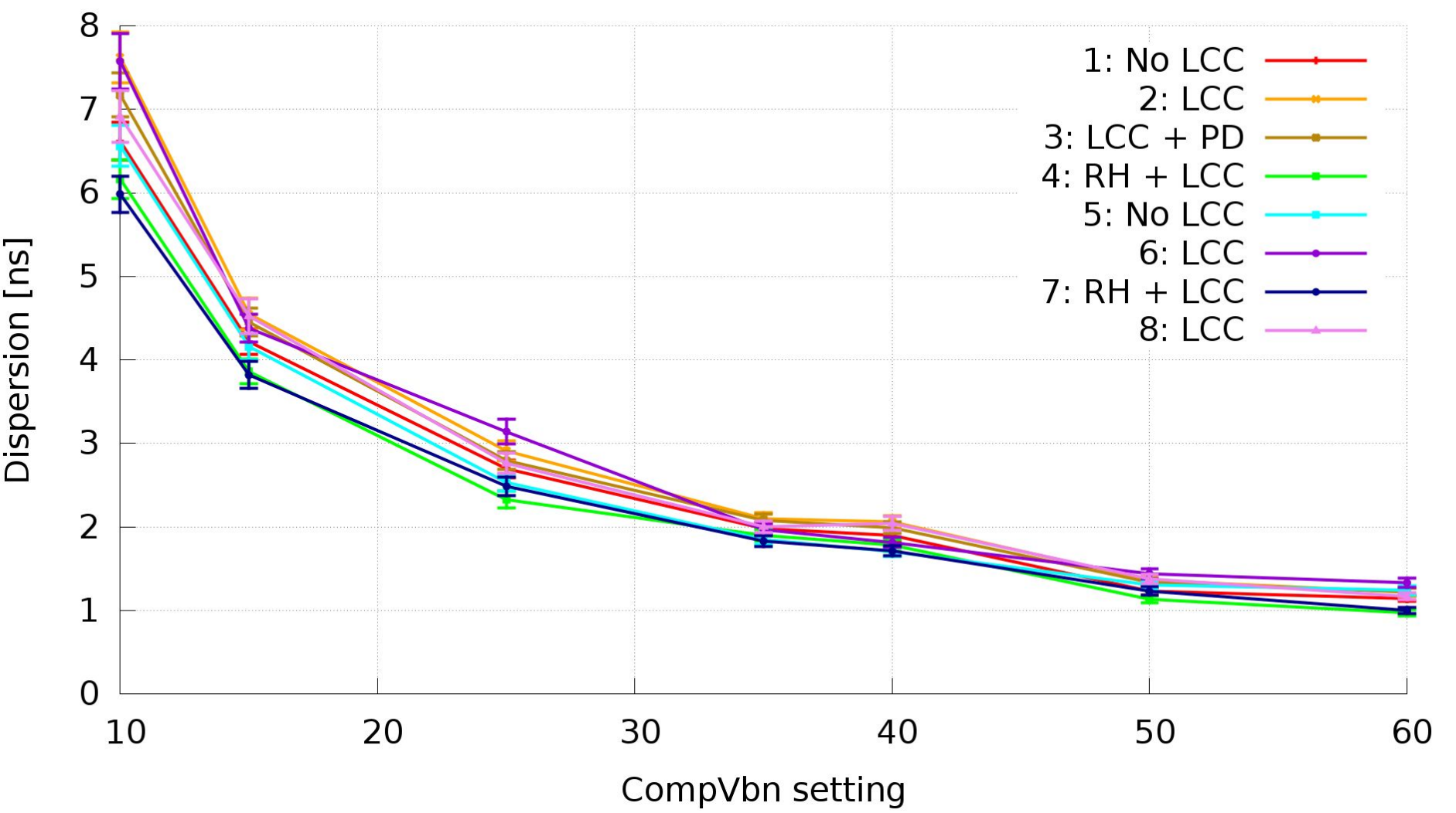








Column Flavor Dispersion



Compare how mean changes with Comparator current

-> have to make latencies comparable

PlsrDelay scans with different Pre-Amp current setting

